



***Evolving ASIC Methodology to Adapt
to Technology and EDA Tool
Advances***

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Agenda

- Technology Advances
- Emerging Challenges
- Design Tool Advances
- ASIC Design Methodology
Implications
- Conclusion

Semiconductor Growth Drivers

WW S/C Revenue (\$B)

10000

1000

100

10

1

1975

1995

Today

2015

Year

Transistors / chip

100B

10B

1B

100M

10M

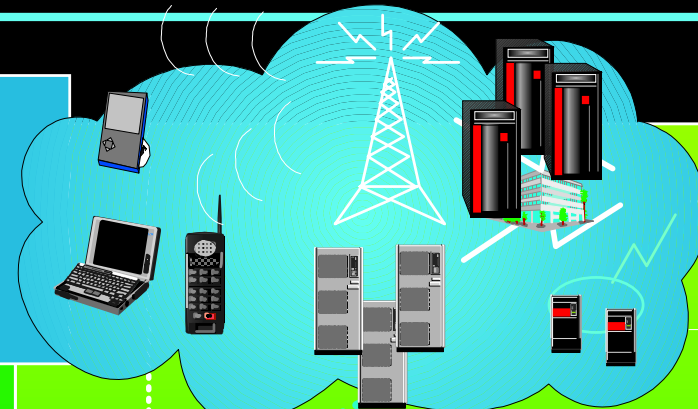
1M

100K

10K

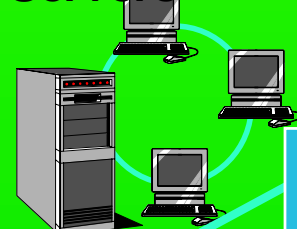
1K

- All businesses, people, objects
- Network computing
- Wide area / bandwidth
- Graphical, voice, multimedia, etc.
- Many vendors / platforms



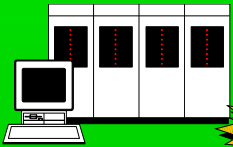
Networks

PCs / Servers



- Businesses & some people
- Client-server computing
- Local area connection
- Text/graphical interface
- Many vendors / few architectures

Mainframes



- Businesses
- Host-based computing
- Mainframe
- Dumb terminal
- Few vendors / architecture

Technology Drivers

- Cost
- High Frequency
- Bandwidth
- Memory
- Power
- Time to Market

*Phones, PDA's, Smart
Clothes...*



*Computers, Net
Storage*

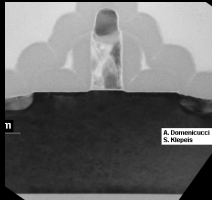


*Routers,
Hubs,
Switches...*



Technology Leadership

Device Technology

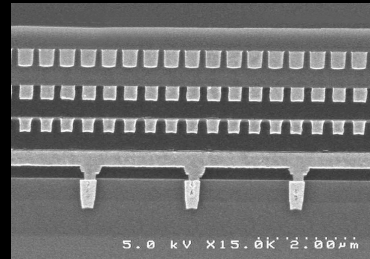


Bulk & SOI CMOS
< 50 nm gates



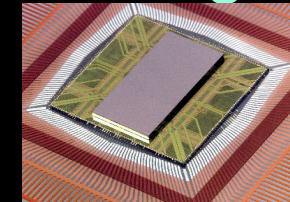
SiGe
BiCMOS
>200ghz

Interconnects



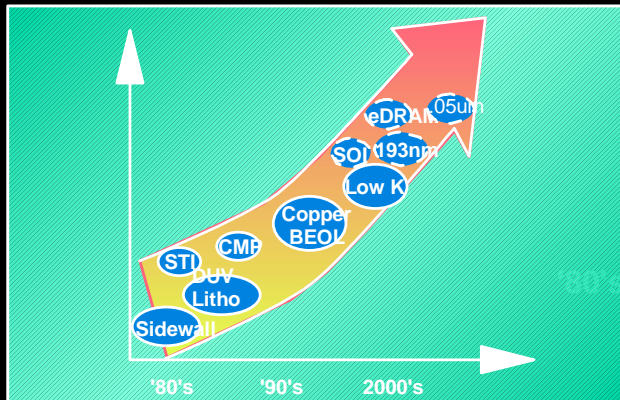
Copper

Packaging

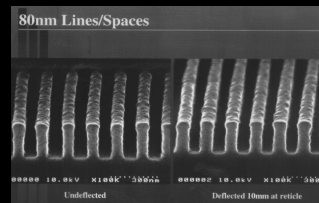


Chip on Chip,
Solder
Bumps, MCM
(polymer
& Ceramic)

Construction Material Changes

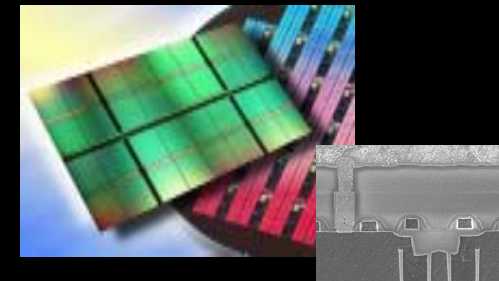


Lithography



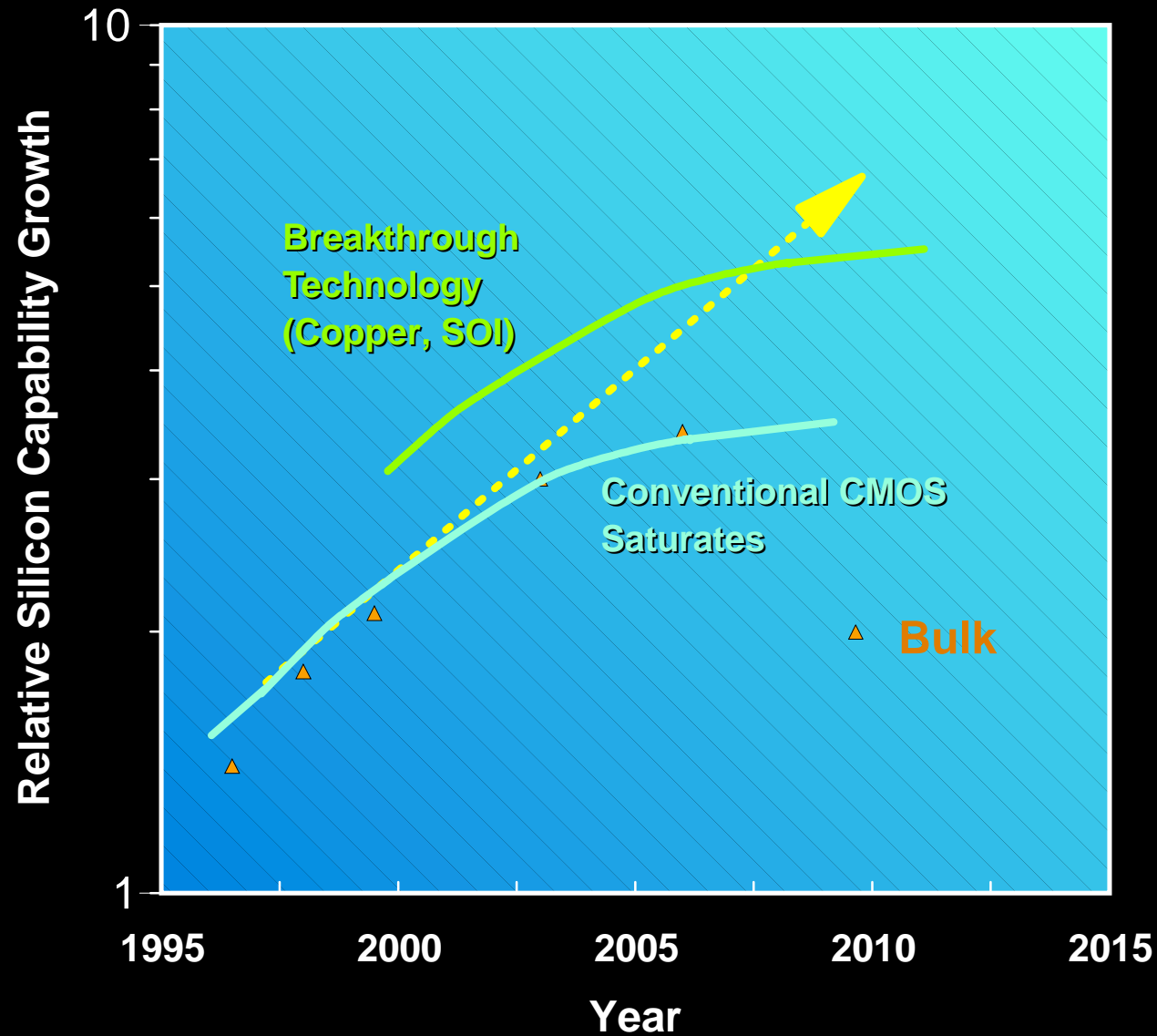
Deep UV, eBeam

Memory

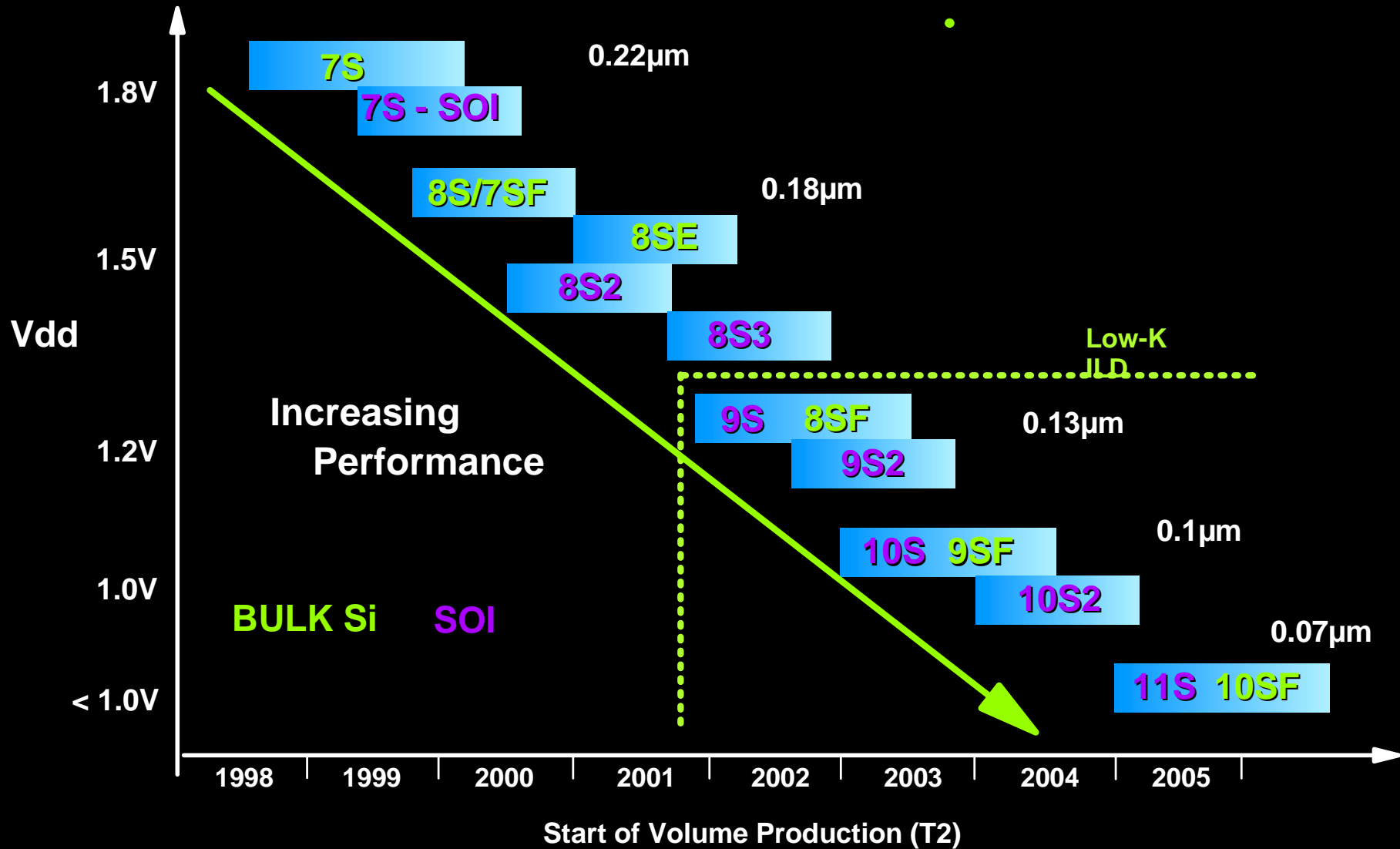


1 Billion Bit Chip,
eDRAM

Require new materials to continue the pace of performance gains



Technology Generation Every 18 - 24 Months



Agenda

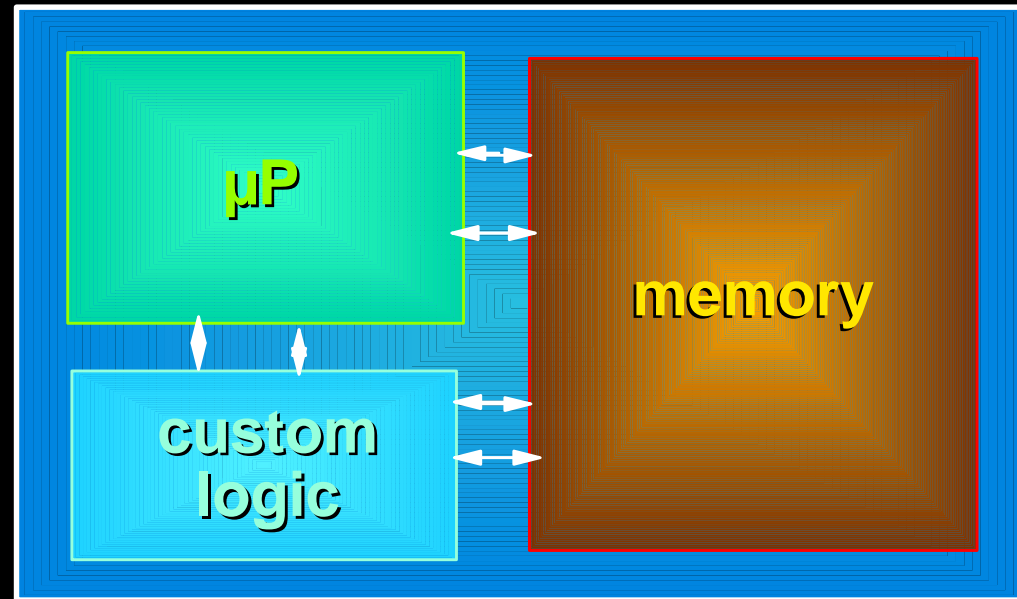
- **Technology Advances**
- **Emerging Challenges**
- **Design Tool Advances**
- **ASIC Design Methodology
Implications**
- **Conclusion**

Low-Power Systems

Various sleep modes

- clock gating
- disabling sub-elements
- disable entire μP

Tradeoff power and performance



Multi-voltage operation

- "power down" non critical circuits
- "power-off" circuits while retaining state

- Control parasitics for lowest leakage
- Circuit design for low voltage, data retention state
- Higher voltage operation for read/write

Low-Power Systems

* Power Tradeoffs Best Made during Architectural Design Phase

- System Issue - Performance, Power, Area
- Requires functional understanding of design
- More leverage than late analysis and fix-up
- Faster tradeoff iteration at higher abstraction

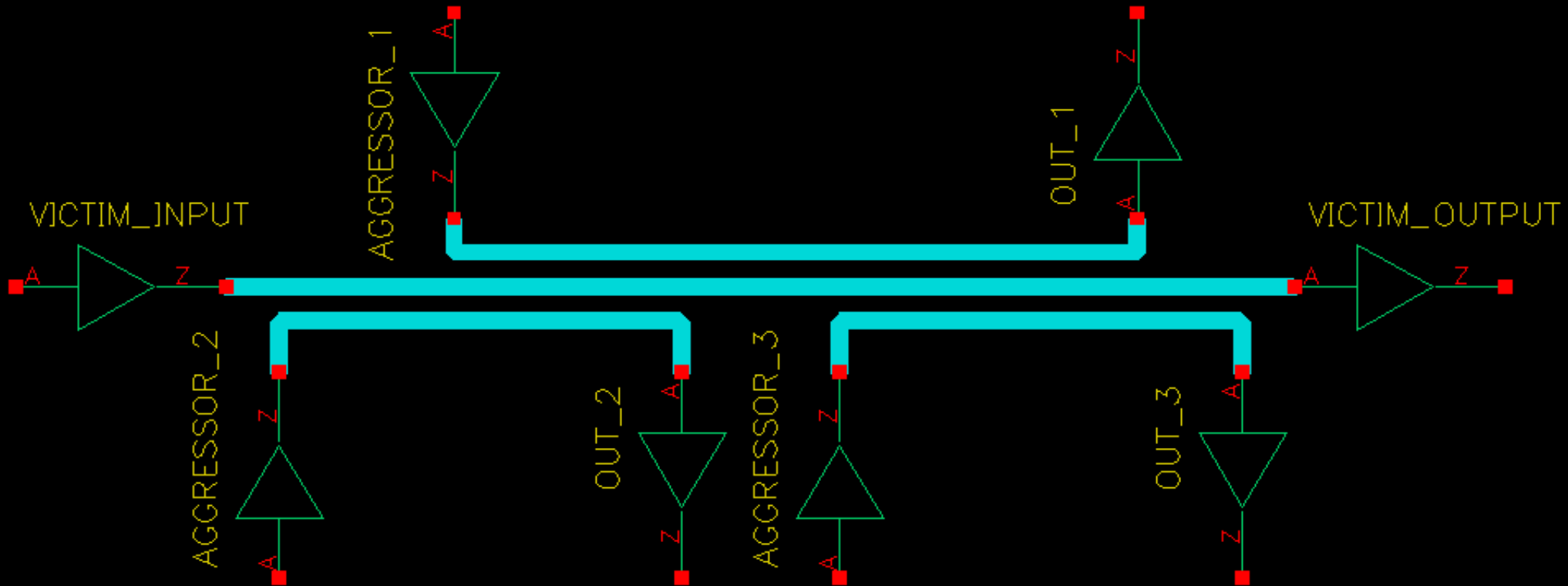
. . . but must have access to technology feature set
(multi-threshold libraries, voltage islands etc.)

* Early Power Analysis Requires Improved Modeling Accuracy

- Technology-specific models for timing accuracy
- Ability to evaluate multiple operating conditions quickly

**Solution involves technology, education, tools, and methodology*

Signal Integrity and Noise



Coupled Noise

- "Aggressor" nets couple signals into "victim" nets
- Coupling primarily due to line-to-line capacitance
- Example shows three aggressors and one victim (A-V-A)
- Many other configurations possible over multiple metal levels

Signal Integrity and Noise

- * **Noise is a progressively worsening problem as geometries shrink**
- * **Could become a gate to customer "first time right" success**
- * **Noise is a complex, multifaceted problem**
 - **Statistical phenomenon**
 - **Several types: coupled, supply, substrate**
 - **Layered approach required to address each type**
- * **Solution involves education, design, tools, and methodology**
- * **Objective is to reduce the probability of a design failure while minimizing impact to design TAT, performance, and density**

Signal Integrity and Noise

- * **Noise is not a new problem - faced by I/O designers for 20+ years**
- * **May cause false switching or timing fails**
- * **Evolved / evolving into an on-chip problem**
- * **Aggravated by many issues:**
 - **Faster chips -> higher edge rates, less Dt tolerance**
 - **Higher edge rates -> more coupled and supply noise**
 - **Lower Vdd -> lower noise immunity**
 - **Wire scaling -> more R, more capacitive coupling ($C_{coupled}/C_{total}$)**
 - **Constant power @ lower Vdd -> more I -> more I-R loss**
 - **Higher I/O Vdd supplies -> increased coupled noise**
 - **Increasing substrate currents -> more substrate noise**

Signal Integrity and Noise

- * **Noise is a statistical phenomenon**

Statistical problems can be significantly reduced but not fully eliminated

- * **Noise reduction can be costly if done without finesse**

Design TAT, performance and density impacts

- "How can I fix 40,000 failing nets?"

- "Why did my critical path slow down by 40%?"

- * **Noise avoidance as important as noise analysis**

- **Limit size of remaining problem to analyze**

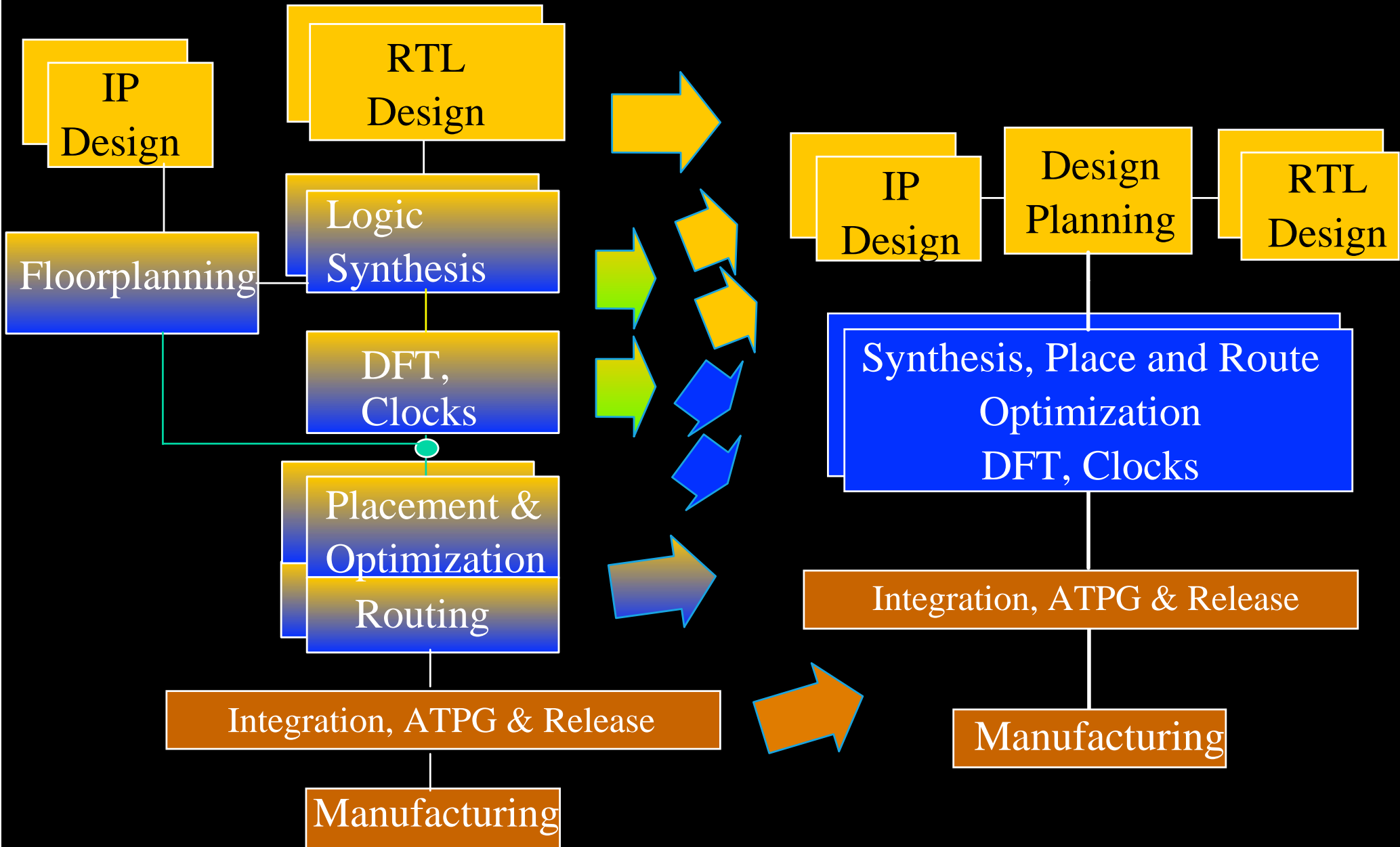
- **Limit number of nets to repair**

Noise avoidance via education, design, tools, and methodology

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ASIC Design Tool Evolution



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Design Methodology Must Evolve

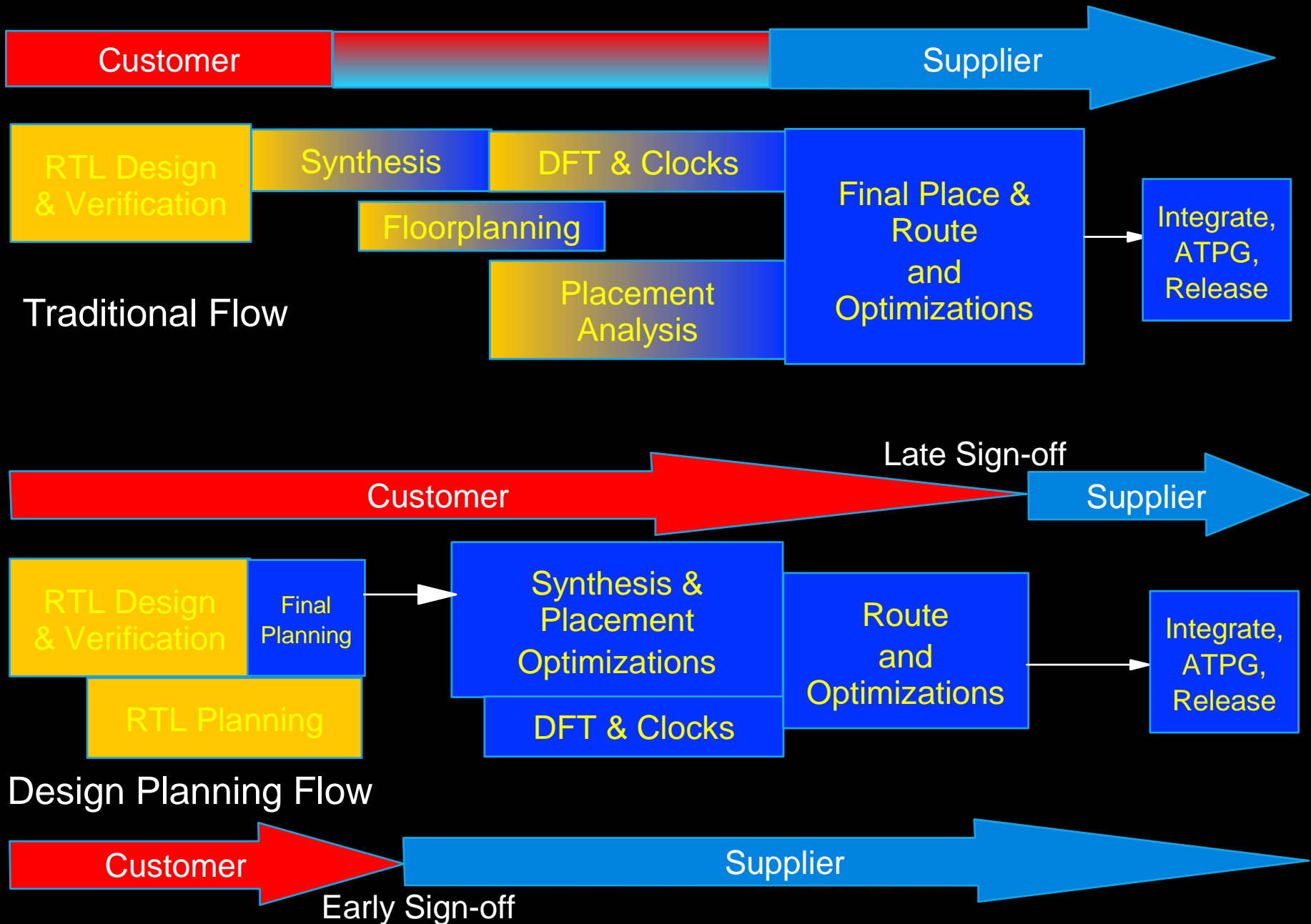
★ To Enable Access to Technology Features

- Early, Architectural-Stage Vision is Essential
 - ▶ Modeling must be evermore accurate in predicting ultimate results
 - ▶ Tool execution must be fast to enable iteration
 - ▶ Issues resolved early yield enormous TAT benefits

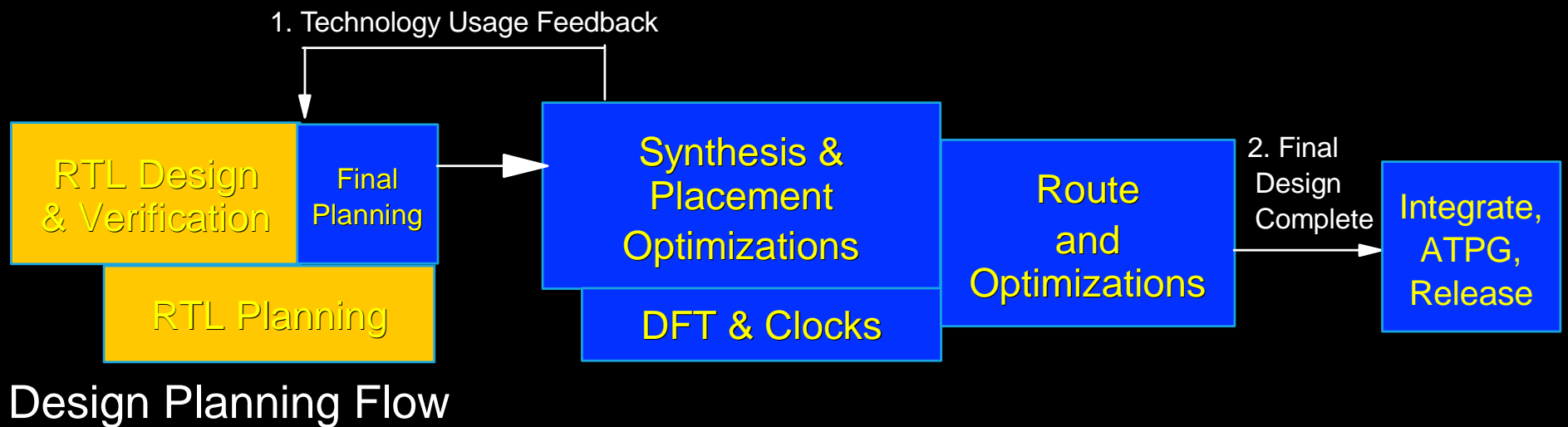
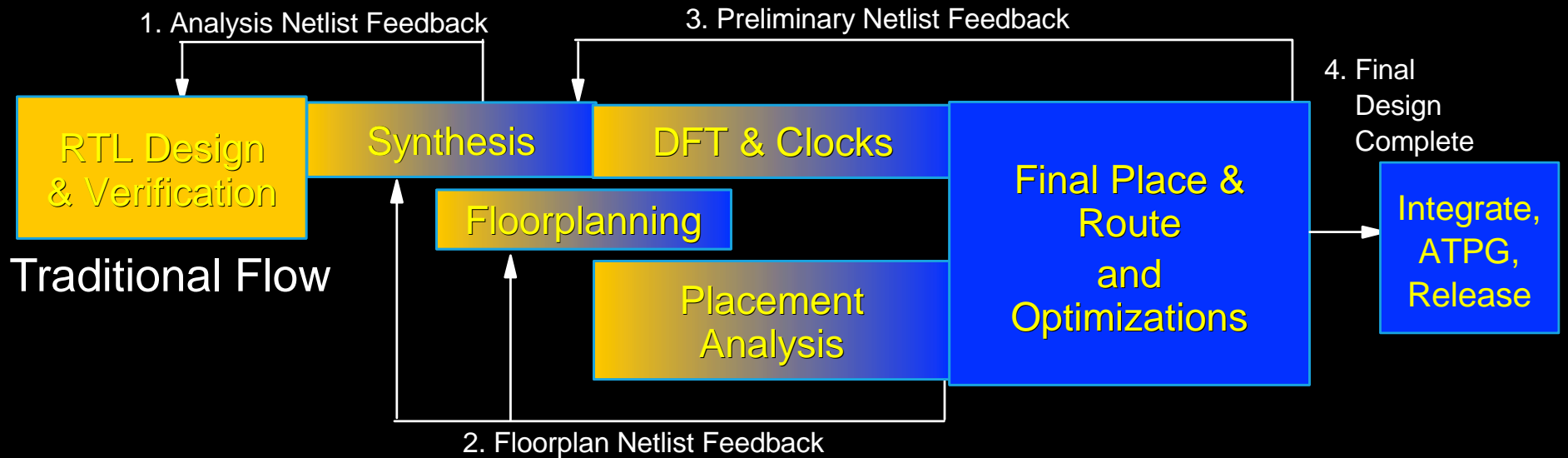
★ To Efficiently Employ New-Generation Design Tools

- Integrated Synthesis, Placement
 - ▶ Dictates "Same Seat" execution of synthesis and placement steps
 - ▶ Sign-off point must move to accommodate
- Advent of Design Planning Tools
 - ▶ Enables Early Focus on Technology Features
 - ▶ Performance, Power, Area, Testability, Cost, Signal Integrity
 - ▶ Key to Accelerating ASIC Turn-around-time

New Design Methodology: Two Engagement Models



New Design Methodology: Efficient and Precise



Modeling Dependencies of the New Methodology

- **Model Accuracy is More Important than Ever**

- For Early Design Planning:

- ▶ Models must enable fast tradeoff experimentation
 - ▶ Must provide visibility into power, timing, area vs. environment, process
 - ▶ Models must enable accurate prediction of downstream results
 - ▶ High-Level Abstraction path
 - ▶ Required accuracy with optimal runtime

- For Detailed Design:

- ▶ Model accuracy must approach 100% precision to overcome pessimism
 - ▶ Accuracy guaranteed by silicon supplier

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ASIC Methodology 2002

★ ASIC Methodology is Evolving to Support Technology and Tool Advances

★ Signoff Model moving In "both directions"

- ▶ Early Signoff
 - ▶ ASIC Supplier Handles Silicon Details
 - ▶ Customer Focus on Function
- ▶ Late Signoff
 - ▶ Customer Owns Both Function and Silicon Implementation

★ There will be ASIC Customers for Both Engagement Models